



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: A1905-01	DATE: 11-Jun-2019	MEANS OF DISTINGUISHING CHANGED DEVICES:
Product Affected: QSOP-16 (Refer to Attachment II for the affected part#)		<input type="checkbox"/> Product Mark Lot # will have: <input checked="" type="checkbox"/> Back Mark "MM" prefix for Carsem, Malaysia (M site) <input type="checkbox"/> Date Code <input type="checkbox"/> Other
Date Effective: 11-Sep-2019		
Contact: IDT PCN DESK	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No	
E-mail: pcndesk@idt.com	Samples: Please contact your local sales representative for sample request.	

DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology	
<input type="checkbox"/> Wafer Fabrication Process	This notification is to advise our customers that IDT is adding Carsem, Malaysia (M site) as an alternate assembly facility as one of the existing assembly facility, OSET has discontinued the package.
<input type="checkbox"/> Assembly Process	
<input type="checkbox"/> Equipment	
<input checked="" type="checkbox"/> Material	There is no change to the moisture performance.
<input type="checkbox"/> Testing	
<input checked="" type="checkbox"/> Manufacturing Site	Attachment I details the qualification results.
<input type="checkbox"/> Data Sheet	Attachment II lists the affected part numbers.
<input type="checkbox"/> Other	

RELIABILITY/QUALIFICATION SUMMARY:
Refer to qualification data shown in Attachment I.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:
IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> Approval for shipments prior to effective date.
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____
CUSTOMER COMMENTS: _____	

IDT ACKNOWLEDGMENT OF RECEIPT:
RECD. BY: _____ DATE: _____

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : A1905-01

PCN Type: Alternate Assembly Location & Change of Material Sets

Data Sheet Change: None

No change in moisture sensitivity level (MSL)

Detail Of Change:

This notification is to advise our customers that IDT is adding Carsem, Malaysia (M site) as an alternate assembly facility as one of the existing assembly facility, OSET has discontinued the package.

The material set details of the current and alternate assembly location is as shown in Table 1. There will be no change in wire type as a result of this PCN. Customers receiving products assembled in Gold wire will continue to receive Gold wire parts and vice versa except for some select part numbers as stated below.

There is no change to the moisture performance rating but the material declaration will differ.

Table 1: Assembly Material Sets for The Existing and Alternate Assembly Location

Material Set / Assembly	Existing		Future	
	ATP - Amkor, Philippines	OSET - OSE, Taiwan	ATP - Amkor, Philippines	CRSM - Carsem, Malaysia (M site)
Die Attach	Ablestik 8290	EN4900GC	Ablestik 8290	84-1 LMI SR4
Bonding Wire	Gold wire, Copper wire	Gold wire	Gold wire, Copper wire	Gold wire, Copper wire*
Mold Compound	EME-G600	CEL-9220HF	EME-G600	CEL-8240HF

* Copper wire for part# 9112BF-17LF(T)

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ATTACHMENT I - PCN # : A1905-01

Qualification Information and Qualification Data:

Affected Packages: QSOP-16

Assembly Material: Shown on page 2 of this attachment.

Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests.

Qualification Vehicle: QSOP-20 (Gold wire) & QSOP-28 (Copper wire)

Test Description	Test Method	Test Results Gold wire & Copper wire (Rej / SS)		
		Lot 1	Lot 2	Lot 3
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/25, 0/25	0/25, 0/25	0/25, 0/25
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/25, 0/25	0/25, 0/25	0/25, 0/25
High Temperature Storage Bake (150°C, 1000 Hrs)	JESD22-A103	0/25, 0/25	0/25, 0/25	0/25, 0/25
X-Ray Examination	IDT Spec. MAC-3012	45/5, 45/5	45/5, 45/5	45/5, 45/5
Ball Shear Test	JESD22-B117	0/5, 0/5	0/5, 0/5	0/5, 0/5
Bond Pull Test	MIL-STD-883 (Method 2011)	0/5, 0/5	0/5, 0/5	0/5, 0/5
Moisture Sensitivity Level, MSL	J-STD-20 / MSL 1, 260 °C	0/25	0/25	-

* Tests were subjected to Preconditioning per JESD22-A113 prior to stress test



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT II - PCN # : A1905-01

Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
74CBTLV3125QG	9112BF-17LFT	QS3257QG	QS3VH253QG8
74CBTLV3125QG8	QS3125QG	QS3257QG8	QS3VH257QG
74CBTLV3251QG	QS3125QG8	QS3VH125QG	QS3VH257QG8
74CBTLV3251QG8	QS3126QG	QS3VH125QG8	QS4A101QG
74CBTLV3253QG	QS3126QG8	QS3VH126QG	QS4A101QG8
74CBTLV3253QG8	QS3251QG	QS3VH126QG8	QS4A205QG
74CBTLV3257QG	QS3251QG8	QS3VH251QG	QS4A205QG8
74CBTLV3257QG8	QS3253QG	QS3VH251QG8	QS4A210QG
9112BF-17LF	QS3253QG8	QS3VH253QG	QS4A210QG8

-IDT Part No-

74CBTLV3125QG

74CBTLV3125QG8

74CBTLV3251QG

74CBTLV3251QG8

74CBTLV3253QG

74CBTLV3253QG8

74CBTLV3257QG

74CBTLV3257QG8

9112BF-17LF

9112BF-17LFT

QS3125QG

QS3125QG8

QS3126QG

QS3126QG8

QS3251QG

QS3251QG8

QS3253QG

QS3253QG8

QS3257QG

QS3257QG8

QS3VH125QG

QS3VH125QG8

QS3VH126QG

QS3VH126QG8

QS3VH251QG

QS3VH251QG8

QS3VH253QG

QS3VH253QG8

QS3VH257QG

QS3VH257QG8

QS4A101QG

QS4A101QG8

QS4A205QG

QS4A205QG8

QS4A210QG

QS4A210QG8